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Anomaly Detection and Imaging with X-Rays (ADIX) VII

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Contents

v *Conference Committee*

SESSION 1 SYSTEM DESIGN, TEST, AND EVALUATION

12104 02 **System and methodology for designing x-ray based simulants for test and evaluation of explosive detection systems** [12104-3]

SESSION 2 ALGORITHMS I

12104 03 **Iterative reconstruction of the electron density and effective atomic number using a non-linear forward model (Invited Paper)** [12104-5]

12104 04 **Robust material classification on dual-energy x-ray imaging devices** [12104-6]

12104 05 **3D x-ray diffraction imaging of optically thin samples** [12104-8]

12104 06 **Augmenting data with GANs for firearms detection in cargo x-ray images** [12104-9]

12104 07 **Synthetic threat injection using digital twin informed augmentation** [12104-10]

SESSION 3 SYSTEMS I

12104 08 **Developing a comprehensive, adaptive system for large scale x-ray images (Invited Paper)** [12104-11]

SESSION 4 DETECTORS AND MATERIALS

12104 0A **Characterization of photon counting detectors for x-ray diffraction (XRD) applications** [12104-15]

12104 0B **Determining the x-ray properties of materials with dual-energy computed tomography and 2D calibration surfaces** [12104-16]

SESSION 5 SYSTEMS II

12104 0C **On the move Compton backscattering scanning (Invited Paper)** [12104-21]

12104 0D **Spectrally responsive edge-illumination (SREI) x-ray phase contrast imaging (XPCI)** [12104-23]

12104 0E **Development of a high-energy x-ray diffractometer for quality control evaluation of next-generation transportation security x-ray imaging systems** [12104-24]

SESSION 6 ALGORITHMS II

12104 0F **Resilient adjudication in non-intrusive inspection with hierarchical object and anomaly detection** [12104-17]

12104 0G **A novel deep learning algorithm to process COVID-19 chest x-rays** [12104-18]

12104 0H **Threat detection in x-ray baggage security imagery using convolutional neural networks** [12104-19]

12104 0I **Comparison of material classification methods using explosive detection system acquired images** [12104-20]

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